

SEMICAPS 4000

INVERTED ANALYTICAL AND *TESTER-DOCKED* SYSTEM

Tester-Docked Conversion



Features

- Analytical or ATE docked configuration
- 300 mm wafer stage including auto-lock compatible with Probe Cards and manipulators
- Docks easily to Tester or Probe Station
- High resolution stage with 0.5 μm repeatability
- Aplanatic Refractive Solid Immersion Lens (ARSIL) option, currently probing 3nm nodes
- CAD interface option
- Analysis Methodologies include a combination of:
 - Laser Timing Probe (LTP)
 - Scanning Optical Microscopy (SOM) with best sensitivity for
 - static analysis: TIVA, OBIRCH
 - dynamic analysis: LADA, SDL
 - Photon Emission Microscopy (PEM) with various options for the InGaAs or Si-CCD camera
 - Thermal Microscopy (THM)

SEMICAPS
Excellence In Innovation

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